Notice of Allowability	Application No.	Applicant(s)	
	10/072,805	KAZUMORI, HIROYOSHI	
	Examiner	Art Unit	
	Paul Gurzo	2881	
The MAILING DATE of this communication appears on the cover sheet with the correspondence address All claims being allowable, PROSECUTION ON THE MERITS IS (OR REMAINS) CLOSED in this application. If not included herewith (or previously mailed), a Notice of Allowance (PTOL-85) or other appropriate communication will be mailed in due course. THIS NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIGHTS. This application is subject to withdrawal from issue at the initiative of the Office or upon petition by the applicant. See 37 CFR 1.313 and MPEP 1308. 1. 1. 1. 1. 1. 1. 1. 1			
2. \(\times\) The allowed claim(s) is/are \(\frac{1-11}{1-11}\).			
The drawings filed on are accepted by the Examiner.			
4. ☐ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f). a) ☐ All b) ☐ Some* c) ☐ None of the:			
Certified copies of the priority documents have been received.			
Certified copies of the priority documents have been received in Application No			
Copies of the certified copies of the priority documents have been received in this national stage application from the International Bureau (PCT Rule 17.2(a)).			
* Certified copies not received:			
5. Acknowledgment is made of a claim for domestic priority under 35 U.S.C. § 119(e) (to a provisional application).			
(a) ☐ The translation of the foreign language provisional application has been received. 6. ☐ Acknowledgment is made of a claim for domestic priority under 35 U.S.C. §§ 120 and/or 121.			
Acknowledgments made of a claim for domestic priority under 35 0.5.0. 99 120 and/or 121.			
Applicant has THREE MONTHS FROM THE *MAILING DATE* of this communication to file a reply complying with the requirements noted below. Failure to timely comply will result in ABANDONMENT of this application. THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.			
7. A SUBSTITUTE OATH OR DECLARATION must be submitted. Note the attached EXAMINER'S AMENDMENT or NOTICE OF INFORMAL PATENT APPLICATION (PTO-152) which gives reason(s) why the oath or declaration is deficient.			
8. CORRECTED DRAWINGS must be submitted. (a) including changes required by the Notice of Draftsperson's Patent Drawing Review (PTO-948) attached 1) including changes required by the proposed drawing correction filed, which has been approved by the Examiner.			
(c) ☐ including changes required by the attached Examiner's Amendment / Comment or in the Office action of Paper No			
Identifying indicia such as the application number (see 37 CFR 1.84(c)) should be written on the drawings in the front (not the back) of each sheet.			
DEPOSIT OF and/or INFORMATION about the deposit of BIOLOGICAL MATERIAL must be submitted. Note the attached Examiner's comment regarding REQUIREMENT FOR THE DEPOSIT OF BIOLOGICAL MATERIAL.			
Attachment(s)			
1 Notice of References Cited (PTO-892) 3 Notice of Draftperson's Patent Drawing Review (PTO-948) 5 Information Disclosure Statements (PTO-1449), Paper No T Examiner's Comment Regarding Requirement for Deposit of Biological Material	4☐ Interview Summa 6☐ Examiner's Ame	al Patent Application (f ary (PTO-413), Paper ndment/Comment ement of Reasons for <i>I</i>	No

Application/Control Number: 10/072,805

Art Unit: 2881

DETAILED ACTION

Allowable Subject Matter

Claims 1-11 are allowed

The following is an examiner's statement of reasons for allowance: As the claimed invention was read in light of the specification, the prior art of record fails to disclose or render obvious a scanning electron microscope and method of detecting electrons produced from a specimen in a scanning electron microscope having an inner polepiece, an outer polepiece, an objective lens forming a magnetic lens field leaking onto a surface of a specimen located under lower end surfaces of the polepieces, the objective lens acting to focus an electron beam onto the specimen, a first opening formed in the inner polepiece and located above the lower end surface of the inner polepiece, and a secondary electron detector mounted outside the inner polepiece to detect secondary electrons passed through the first opening, wherein a negative voltage is applied to the specimen to produce a decelerating electric field near the surface of the specimen to decelerate the electron beam, wherein there is provided a conversion electrode on which secondary electrons emitted from the specimen impinge, the conversion electrode being mounted around an electron beam passage inside the objective lens, and wherein secondary electrons emitted from said conversion electrode are guided via said first opening to said secondary electron detector and detected.

The closest prior art, Ose et al. and Takaoka et al., teach the use of an inner and outer polepiece, objective lens, secondary electron detector, negative voltage application, and conversion electrode. However, they are silent about the claimed openings in the polepieces and a conversion electrode mounted around an electron beam inside the objective lens.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Paul Gurzo whose telephone number is (703) 306-0532. The examiner can normally be reached on M-Thurs. 7:30 - 6:00.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, John Lee can be reached on (703) 308-4116. The fax phone numbers for the organization where this application or proceeding is assigned are (703) 872-9318 for regular communications and (703) 872-9319 for After Final communications.

Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the receptionist whose telephone number is (703) 308-0956.

PMG October 29, 2003

JOHN R. LEE